Measurement of $K\alpha$ and $K\beta$ fluorescence cross sections for elements in the range $44 \le Z \le 68$ at 59.5 keV

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The $K\alpha$ and $K\beta$ x-ray fluorescence cross sections have been measured for elements in the range $44 \le Z \le 68$ at an excitation energy of 59.5-keV γ ray from ²⁴¹Am radioisotope with a Si(Li) detector. A reasonable agreement is found between the present experimental results and the theoretically calculated values based on photoionization cross sections by Scofield using Hartree-Slater and Hartree-Fock central potential theory. [S1050-2947(99)03409-5]

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I. INTRODUCTION

Information regarding the experimental values of K x-ray fluorescence (XRF) cross sections for different elements at various photoionization energies is important because of its wide use in atomic, molecular, and radiation physics and in the nondestructive elemental analysis of materials using energy-dispersive x-ray fluorescence. On the other hand, accurate knowledge of cross section data makes XRF very suitable for quantitative elemental analysis.

Several attempts have been made for measuring XRF cross sections and yields. Kraus *et al.* [1] have calculated theoretically *K* and *L* XRF cross sections but there have been few reports on experimental measurements of XRF cross sections. Bahn, Chaturvedi, and Nah [2] determined *K*-shell cross sections for ten elements with $18 \le Z \le 48$ at two excitation energies from ¹⁰⁹Cd and ¹²⁵I radioisotopes. Garg *et al.* [3] measured $K\alpha$ and $K\beta$ cross sections at ten excitation energies ranging from 5.9 to 59.54 keV for elements with $20 \le Z \le 56$.

In recent years, *K*-shell fluorescence yields and cross sections for several elements have been measured by many authors [4–10]. Durak *et al.* [6] have measured *K*-shell fluorescence cross sections for some elements with $40 \le Z \le 70$ at 122-keV incident photon energy. Rao, Cesareo, and Gigante [8] have reported some measurements of *K* XRF cross sections for low-*Z* elements at low excitation energies. Puri *et al.* [11] have calculated *K* and *L* shell x-ray fluorescence cross sections for elements with $13 \le Z \le 92$ and $35 \le Z \le 92$, respectively, at 1–200-keV incident photon energy range.

In this paper $K\alpha$ and $K\beta$ XRF cross sections are measured for the elements with $44 \le Z \le 68$ at the excitation energy 59.537 keV of ²⁴¹Am radioisotopes. The experimental results are compared with theoretical values.

II. EXPERIMENTAL PROCEDURES

The experimental arrangement and geometry used in the present measurements are shown in Fig. 1. In this arrangement low-energy photon sources of ²⁴¹Am (100 mCi) were used, and the energy of the primary photons are 59.537 keV for ²⁴¹Am. Spectroscopically pure (purity better than 99.9%)

samples of thickness ranging from 20–55 mg/cm⁻² have been used for the measurements. The *K* x-ray spectra from various materials were recorded with the collimated Si(Li) detector with an active area of 12.5 mm², sensitive crystal depth of 3.5 cm, and a Be window of 2.5-mm thickness coupled to a 1024 channel ND 66B analyzer through a spectroscope amplifier. The energy resolution of the Si(Li) detector was 190-eV full width at half maximum at 5.9 keV (⁵⁵Fe). In order to reduce the statistical error in the measurements, three sets of observations were taken for each target for time intervals ranging from 1000–10 000 s. For the overlapped peaks, net peak areas were determined with the method developed in our earlier publication [12]. A typical x-ray spectra of Dy is shown in Fig. 2.

III. DATA ANALYSIS

Calculation of the K XRF cross sections. The theoretical K x-ray fluorescence cross sections σ_{Ki} were calculated using the fundamental parameter equation

$$\sigma_{Ki} = \sigma_K^P(E) \omega_K f_{Ki} \quad (i = \alpha, \beta), \tag{1}$$

where $\sigma_K^P(E)$ is the *K*-shell photoionization cross section for the given elements at excitation energy *E*, ω_K is the fluorescence yields of the *K*-shell line, f_{Ki} is the fractional ratio of the *Ki* x-rays, and $f_{K\alpha}$ and $f_{K\beta}$ are defined as





FIG. 1. Experiment setup.

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FIG. 2. K x-ray spectrum of Dy excited by 59.537 keV.



where $I_{K\beta}/I_{K\alpha}$ is the $K\beta$ to $K\alpha$ x-ray intensity ratio.

In the present calculations, the values of $\sigma_K^P(E)$ were taken from Scofield [13] based on Hartree-Slater (HS) potential theory and the values of ω_K were taken from an annotated bibliography by Hubbel *et al.* [4]. Two sets of values of $I_{K\beta}/I_{K\alpha}$ intensity ratios were used for the evaluation of theoretical *K* XRF cross sections, one based on HS theory [14] and the other on Hartree-Fock (HF) theory [15].

Measurement of the K XRF cross sections. The experimental K x-ray fluorescence cross sections σ_{Ki} for a given element were evaluated using the equation

$$\sigma_i = \frac{N_{Ki}}{I_0 G \varepsilon_K \beta_{Ki} t} \quad (i = \alpha, \beta), \tag{3}$$

where N_{Ki} is the number of counts per unit time under Kix-ray peak of the given elements, I_0G is the intensity of exciting radiation falling on the sample, ε_{Ki} is the detector efficiency for the K x rays, t is the mass in g/cm⁻² of the element, and β_{Ki} is the target self-absorption correction for both the incident and the emitted characteristic x-rays radia-

| Element-Z | $\sigma_{K\alpha}$ (barns) | | | | $\sigma_{K\beta}$ (barns) | | | |
|-----------|----------------------------|--------|---------------------|---------------------|---------------------------|--------|---------------------|---------------------|
| | Expt. | Fitted | Theor. ^a | Theor. ^b | Expt. | Fitted | Theor. ^a | Theor. ^b |
| Ru-44 | 467± 33 | 469 | 447 | | 93± 8 | 90 | 84 | |
| Rh-45 | | 514 | 496 | | | 102 | 95 | |
| Pd-46 | 562± 39 | 563 | 545 | | 114 ± 10 | 114 | 105 | |
| Ag-47 | с | 616 | 596 | 588 | 123±11 | 128 | 117 | 125 |
| Cd-48 | $660\pm~38$ | 668 | 650 | | 139±12 | 142 | 130 | |
| In-49 | 739± 54 | 725 | 706 | | 162±15 | 157 | 143 | |
| Sn-50 | 773± 56 | 785 | 765 | 755 | 164±15 | 172 | 158 | 168 |
| Sb-51 | 846± 63 | 847 | 827 | 816 | 191 ± 17 | 189 | 173 | 185 |
| Te-52 | с | 913 | 891 | | 215±17 | 206 | 190 | |
| I-53 | 994± 73 | 981 | 958 | | 231 ± 21 | 224 | 208 | |
| Xe-54 | | 1052 | 1026 | 1012 | | 243 | 226 | 240 |
| Cs-55 | 1139± 85 | 1126 | 1097 | | 268 ± 25 | 263 | 246 | |
| Ba-56 | 1200± 86 | 1202 | 1173 | 1158 | 291±27 | 283 | 267 | 282 |
| La-57 | 1258 ± 91 | 1282 | 1251 | | 298 ± 27 | 304 | 288 | |
| Ce-58 | с | 1364 | 1337 | | 323 ± 30 | 326 | 310 | |
| Pr-59 | $1468\pm$ 88 | 1449 | 1418 | | 355 ± 32 | 349 | 331 | |
| Nd-60 | 1539± 93 | 1537 | 1504 | 1486 | 382 ± 35 | 377 | 354 | 378 |
| Pm-61 | | 1628 | 1592 | | | 397 | 378 | |
| Sm-62 | 1724 ± 105 | 1722 | 1678 | | 414±36 | 422 | 401 | |
| Eu-63 | с | 1818 | 1774 | 1753 | 446±36 | 448 | 427 | 447 |
| Gd-64 | 1882 ± 112 | 1917 | 1869 | 1847 | 462 ± 37 | 475 | 453 | 475 |
| Tb-65 | 2025 ± 118 | 2019 | 1968 | 1946 | 512 ± 40 | 503 | 479 | 501 |
| Dy-66 | 2088 ± 120 | 2124 | 2063 | | 517±39 | 531 | 505 | |
| Ho-67 | 2278 ± 132 | 2232 | 2218 | | 580 ± 43 | 560 | 546 | |
| Er-68 | с | 2342 | 2301 | 2276 | 594±47 | 590 | 570 | 594 |

TABLE I. $K\alpha$ and $K\beta$ XRF cross sections.

^aValues calculated using $I_{K\beta}/I_{K\alpha}$ based on HS theory [14].

^bValues calculated using $I_{K\beta}/I_{K\alpha}$ based on HF theory [15].

^cThe $K\alpha$ x rays of these elements were utilized to evaluate the $I_0G\epsilon_K$ values.



FIG. 3. (a) $K\alpha$ x-ray fluorescence cross sections. (b) $K\beta$ x-ray fluorescence cross sections.

tion. The values of β_{Ki} have been calculated by using the following expression obtained by assuming that the fluorescent x rays have a normal incidence to the detector:

$$\beta_{K} = \frac{1 - \exp[-(\mu_{\text{inc}}/\cos\theta_{1} + \mu_{\text{emt}}/\cos\theta_{2})t]}{(\mu_{\text{inc}}/\cos\theta_{1} + \mu_{\text{emt}}/\cos\theta_{2})t}, \quad (4)$$

where μ_{inc} and μ_{emt} are the total attenuation coefficients [16] at primary and emitted x-ray photon energies, respectively. $\theta_1(=45)$ and $\theta_2(=45)$ are the angles with the sample normal primary and emitted K x rays. The effective incident photon flux elements $I_0G\varepsilon_K$ was evaluated by measuring the K x-ray fluorescence cross sections from Mo, Ag, Te, Ce, Eu, and Er in the same geometry. The weighted average of the $I_0G\varepsilon_K$ values obtained from different samples was taken. The errors in the efficiency values in this energy are estimated to be less than 3%.

IV. RESULTS AND DISCUSSION

The *K* x-ray fluorescence cross sections of the elements in the atomic range $44 \le Z \le 68$ are listed in Table I. They are

plotted as a function of the atomic number in Fig. 3. It can be seen from Table I and Fig. 3 that the present values are in good agreement within the experimental uncertainties with theoretical values calculated using emission rates (f_{Ki}) based on HF theory and HS potential theory. In addition, these experimental values were fitted to a second-order polynomial and are listed in Table I found values for the fluorescence cross sections. The overall error in the measured $K\alpha$ and $K\beta$ XRF cross sections are estimated to be less than 7% and 9%, respectively. These errors are attributed to the uncertainties in the different parameters using the Eq. (2). The error in the evaluation of area under the $K\alpha$ and $K\beta$ x-ray peak is about 1% and 3%, respectively [12]; the error in $I_0 G \varepsilon_K$ is less than 3%, the error in the target thickness measurements is on the order of 2%, and the error in the absorption correction β is less than 2%. The uncertainty in the area of the K x-ray peak was evaluated by the weighted average method.

As a result, the present agreement between the theoretical and the present experimental values leads to the conclusion that the data presented here will benefit those using radioisotope XRF technique for elemental analysis.

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